

**Search Notes**

Application/Control No.

10/052,870

Examiner

Jason M. Perilla

Applicant(s)/Patent under  
Reexamination

SHI ET AL.

Art Unit

2611

**SEARCHED**

Class	Subclass	Date	Examiner
375	219	9/1/2006	JP
	316	9/1/2006	JP
	324	9/1/2006	JP
	344	9/1/2006	JP
	345	9/1/2006	JP
	346	9/1/2006	JP
455	130	9/1/2006	JP

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
375	316	9/1/2006	JP
	324	9/1/2006	JP

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East USPAT USPGPUB EPO JPO	9/1/2006	JP
Inventor Name Search EAST/EDAN	9/1/2006	JP